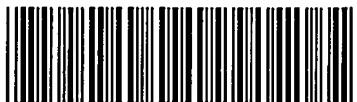


Search Notes**Application/Control No.**

10/646,823

Examiner

Hai L. Nguyen

Applicant(s)/Patent under Reexamination

ISHIMI, KOICHI

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
327	116,119, 146,147, 149,151, 158	4/17/2005	HLN
	153-156		
	160-163		
	291-294		
331	25,34,53		
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375	373-376	↓	↓

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Shepardize Search	4/17/2005	HLN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Search	Above	4/17/2005	HLN